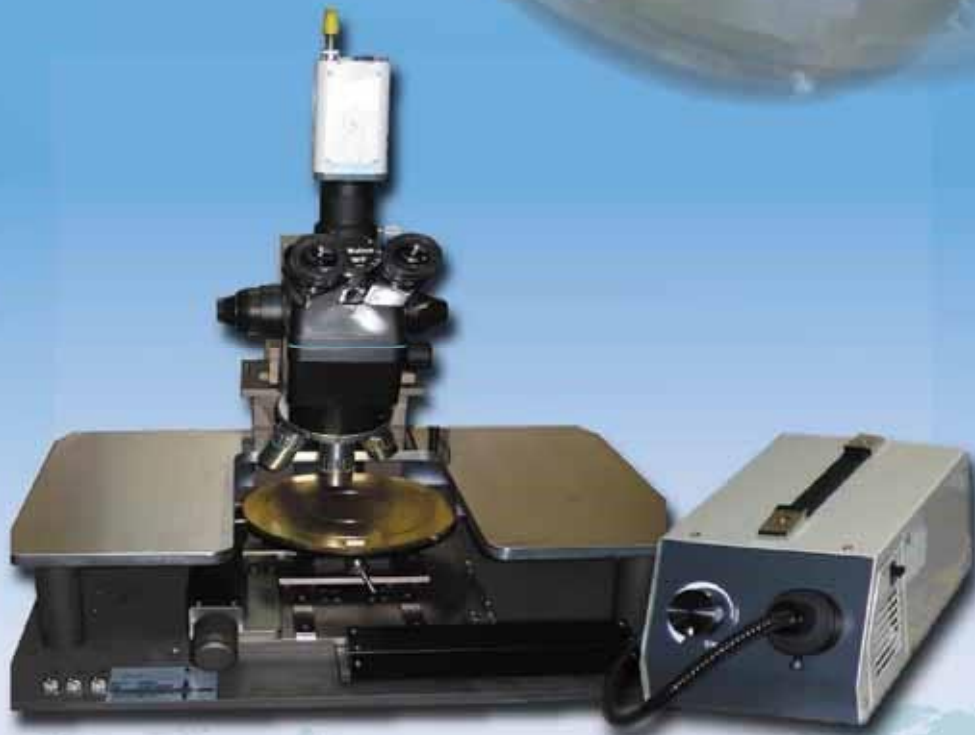


**ANALYTICAL PROBE STATION**

# **APS 150/200**



**MICROTEST**

Equipment & Consumables for the  
semiconductors and hybrids



**Swin**

## APS Series Probe Station (APS 150/200)

### Features

- Hinged-Knob Chuck stage
- Ball Screw Driven Chuck Stage
- RF Probing Field Upgradeable
- Backlash-Free Movement
- High Magnification Microscope Compatible

### Specifications

- Vacuum chuck : 150mm/ 200mm stainless steel
- Chuck stage travel :
  - APS 150 : 150mm x 150mm
  - APS 200 : 200mm x 200mm
- Chuck theta : 0~30degree
- Chuck up / down : 5mm
- Microscope stage travel : 25 x 25mm
- Platen movement : fixed
- Sample Size: 5x5mm ~ 150 / 200mm
- Chuck Flatness: 10um



### Dimensions

- Dimension(W/D/H) :
  - APS 150 : 580mm x 460mmD x 700mm
  - APS 200 : 660mm x 660mmD x 700mm
- Weight : 60kg (APS 150) , 80kg (APS 200)

### Options

- Gold Plated Vacuum Chuck
- Thermal Systems
- Chuck Vacuum Pattern
- Pneumatic microscope lift for objective changer over
- RF Probes/Cables
- Active Probes
- Low Current/Capacitance Probes
- High Voltage Probes
- Laser Cutter
- CCD/Digital Camera with USB Connection
- Vibration Free Table
- Shielding Box
- Instrument Case with Caster

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